

August 1997 - Revised May 2000

High Speed CMOS Logic Hex D-Type Flip-Flop with Reset

Features

- Buffered Positive Edge Triggered Clock
- Asynchronous Common Reset
- Fanout (Over Temperature Range)
 - Standard Outputs 10 LSTTL Loads
 - Bus Driver Outputs 15 LSTTL Loads
- Wide Operating Temperature Range . . . -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
 - 2V to 6V Operation
 - High Noise Immunity: $N_{IL} = 30\%$, $N_{IH} = 30\%$ of V_{CC} at $V_{CC} = 5V$
- HCT Types
 - 4.5V to 5.5V Operation
 - Direct LSTTL Input Logic Compatibility, $V_{IL} = 0.8V$ (Max), $V_{IH} = 2V$ (Min)
 - CMOS Input Compatibility, $I_I \leq 1\mu A$ at V_{OL} , V_{OH}

Description

The 'HC174 and 'HCT174 are edge triggered flip-flops which utilize silicon gate CMOS circuitry to implement D-type flip-flops. They possess low power and speeds comparable to low power Schottky TTL circuits. The devices contain six master-slave flip-flops with a common clock and common reset. Data on the D input having the specified setup and hold times is transferred to the Q output on the low to high

transition of the CLOCK input. The $\overline{MR}$ input, when low, sets all outputs to a low state.

Each output can drive ten low power Schottky TTL equivalent loads. The 'HCT174 is functional as well as, pin compatible to the 'LS174.

Ordering Information

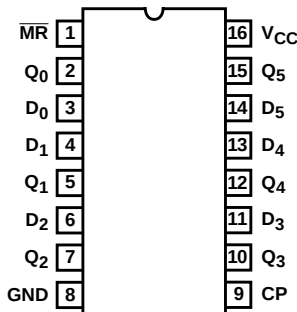
PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD54HC174F	-55 to 125	16 Ld CERDIP
CD54HC174F3A	-55 to 125	16 Ld CERDIP
CD74HC174E	-55 to 125	16 Ld PDIP
CD74HC174M	-55 to 125	16 Ld SOIC
CD54HCT174F	-55 to 125	16 Ld CERDIP
CD54HCT174F3A	-55 to 125	16 Ld CERDIP
CD74HCT174E	-55 to 125	16 Ld PDIP
CD74HCT174M	-55 to 125	16 Ld SOIC
CD74HCT174W	-55 to 125	Wafer

NOTES:

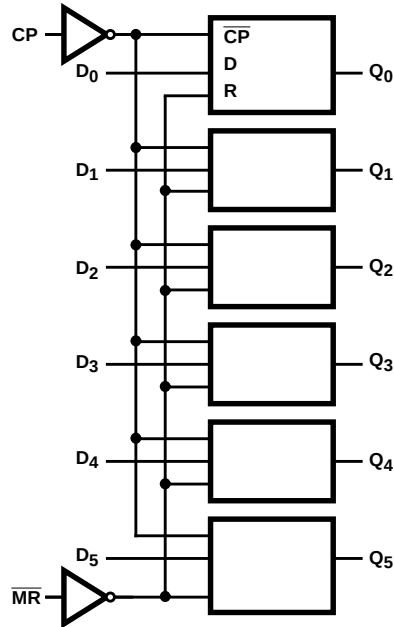
1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Die for this part number is available which meets all electrical specifications. Please contact your local TI sales office or customer service for ordering information.

Pinout

CD54HC174, CD54HCT174
(CERDIP)
CD74HC174, CD74HCT174
(PDIP, SOIC)
TOP VIEW



Functional Diagram

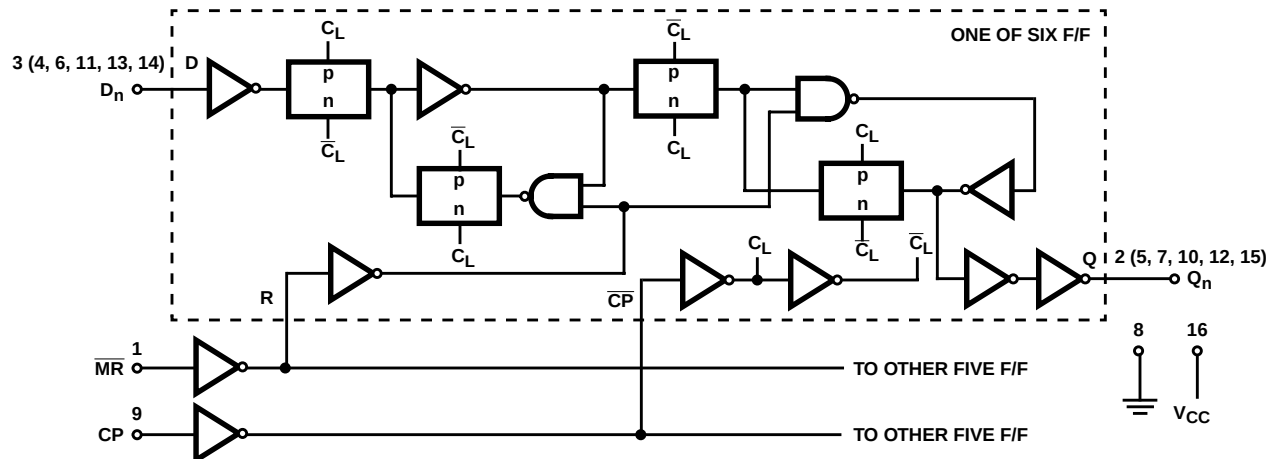


TRUTH TABLE

INPUTS			OUTPUT
RESET ($\overline{MR}$)	CLOCK CP	DATA D_n	Q_n
L	X	X	L
H	$\uparrow$	H	H
H	$\uparrow$	L	L
H	L	X	Q_0

NOTE: H = High Voltage Level, L = Low Voltage Level, X = Irrelevant, $\uparrow$ = Transition from Low to High Level, Q_0 = Level Before the Indicated Steady-State Input Conditions Were Established

Logic Diagram



CD54/74HC174, CD54/74HCT174

Absolute Maximum Ratings

DC Supply Voltage, V_{CC}	-0.5V to 7V
DC Input Diode Current, I_{IK}	
For $V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$	$\pm 20mA$
DC Output Diode Current, I_{OK}	
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$	$\pm 20mA$
DC Output Source or Sink Current per Output Pin, I_O	
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$	$\pm 25mA$
DC V_{CC} or Ground Current, I_{CC} or I_{GND}	$\pm 50mA$

Thermal Information

Thermal Resistance (Typical, Note 3)	θ_{JA} ($^{\circ}C/W$)
PDIP Package	85
SOIC Package	110
Maximum Junction Temperature	$150^{\circ}C$
Maximum Storage Temperature Range	$-65^{\circ}C$ to $150^{\circ}C$
Maximum Lead Temperature (Soldering 10s)	$300^{\circ}C$
(SOIC - Lead Tips Only)	

Operating Conditions

Temperature Range (T_A)	$-55^{\circ}C$ to $125^{\circ}C$
Supply Voltage Range, V_{CC}	
HC Types	.2V to 6V
HCT Types	.4.5V to 5.5V
DC Input or Output Voltage, V_I , V_O	0V to V_{CC}
Input Rise and Fall Time	
2V	1000ns (Max)
4.5V	500ns (Max)
6V	400ns (Max)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

- θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		V _{CC} (V)	25°C			-40°C TO +85°C		-55°C TO 125°C		UNITS
		V _I (V)	I _O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HC TYPES												
High Level Input Voltage	V _{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V
				4.5	3.15	-	-	3.15	-	3.15	-	V
				6	4.2	-	-	4.2	-	4.2	-	V
Low Level Input Voltage	V _{IL}	-	-	2	-	-	0.5	-	0.5	-	0.5	V
				4.5	-	-	1.35	-	1.35	-	1.35	V
				6	-	-	1.8	-	1.8	-	1.8	V
High Level Output Voltage CMOS Loads	V _{OH}	V _{IH} or V _{IL}	-0.02	2	1.9	-	-	1.9	-	1.9	-	V
			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
			-0.02	6	5.9	-	-	5.9	-	5.9	-	V
High Level Output Voltage TTL Loads	V _{OH}	V _{IH} or V _{IL}	-4	4.5	3.98	-	-	3.84	-	3.7	-	V
			-5.2	6	5.48	-	-	5.34	-	5.2	-	V
Low Level Output Voltage CMOS Loads	V _{OL}	V _{IH} or V _{IL}	0.02	2	-	-	0.1	-	0.1	-	0.1	V
			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
			0.02	6	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads	V _{OL}	V _{IH} or V _{IL}	4	4.5	-	-	0.26	-	0.33	-	0.4	V
			5.2	6	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I _I	V _{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	µA
Quiescent Device Current	I _{CC}	V _{CC} or GND	0	6	-	-	8	-	80	-	160	µA

CD54/74HC174, CD54/74HCT174

DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V _{CC} (V)	25°C			-40°C TO +85°C		-55°C TO 125°C		UNITS
		V _I (V)	I _O (mA)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	
HCT TYPES												
High Level Input Voltage	V _{IH}	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V _{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V _{OH}	V _{IH} or V _{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V _{OL}	V _{IH} or V _{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	I _I	V _{CC} to GND	0	5.5	-	-	±0.1	-	±1	-	±1	μA
Quiescent Device Current	I _{CC}	V _{CC} or GND	0	5.5	-	-	8	-	80	-	160	μA
Additional Quiescent Device Current Per Input Pin: 1 Unit Load (Note 4)	ΔI _{CC}	V _{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μA

NOTE:

- For dual-supply systems theoretical worst case (V_I = 2.4V, V_{CC} = 5.5V) specification is 1.8mA.

HCT Input Loading Table

INPUT	UNIT LOADS
CP	0.80
MR	0.55
D	0.15

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Specifications table, e.g. 360μA max at 25°C.

Prerequisite For Switching Function

PARAMETER	SYMBOL	TEST CONDITIONS	V _{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	MAX	MIN	MAX	MIN	MAX	
HC TYPES										
Clock Pulse Width	t _w	-	2	80	-	100	-	120	-	ns
			4.5	16	-	20	-	24	-	ns
			6	14	-	17	-	20	-	ns
MR Pulse Width	t _w	-	2	80	-	100	-	120	-	ns
			4.5	16	-	20	-	24	-	ns
			6	14	-	17	-	20	-	ns

CD54/74HC174, CD54/74HCT174

Prerequisite For Switching Function (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS	V _{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS
				MIN	MAX	MIN	MAX	MIN	MAX	
Setup Time, Data to Clock	t _{SU}	-	2	60	-	75	-	90	-	ns
			4.5	12	-	15	-	18	-	ns
			6	10	-	13	-	15	-	ns
Hold Time, Data to Clock	t _H	-	2	5	-	5	-	5	-	ns
			4.5	5	-	5	-	5	-	ns
			6	5	-	5	-	5	-	ns
Removal Time, $\overline{\text{MR}}$ to Clock	t _{REM}	-	2	5	-	5	-	5	-	ns
			4.5	5	-	5	-	5	-	ns
			6	5	-	5	-	5	-	ns
Clock Frequency	f _{MAX}	-	2	6	-	5	-	4	-	MHz
			4.5	30	-	24	-	20	-	MHz
			6	35	-	28	-	24	-	MHz

HCT TYPES

Clock Pulse Width	t _w	-	4.5	20	-	25	-	30	-	ns
$\overline{\text{MR}}$ Pulse Width	t _w	-	6	25	-	31	-	38	-	ns
Setup Time, Data to Clock	t _{SU}	-	4.5	16	-	20	-	24	-	ns
Hold Time, Data to Clock	t _H	-	6	5	-	5	-	5	-	ns
Removal Time, $\overline{\text{MR}}$ to Clock	t _{REM}	-	4.5	12	-	15	-	18	-	ns
Clock Frequency	f _{MAX}	-	6	25	-	20	-	17	-	MHz

Switching Specifications Input t_r, t_f = 6ns

PARAMETER	SYMBOL	TEST CONDITIONS	V _{CC} (V)	25°C		-40°C TO 85°C	-55°C TO 125°C	UNITS
				TYP	MAX	MAX	MAX	
HC TYPES								
Propagation Delay, Clock to Q	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	165	205	250	ns
			4.5	-	33	41	50	ns
			6	-	28	35	43	ns
		C _L = 15pF	5	13	-	-	-	ns
Propagation Delay, $\overline{\text{MR}}$ to Q	t _{PLH} , t _{PHL}	C _L = 50pF	2	-	150	190	225	ns
			4.5	-	30	38	45	ns
			6	-	26	33	38	ns
		C _L = 15pF	5	12	-	-	-	ns
Output Transition Times	t _{TLH} , t _{THL}	C _L = 50pF	2	-	75	95	110	ns
			4.5	-	15	19	22	ns
			6	-	13	16	19	ns
Input Capacitance	C _{IN}	-	-	-	10	10	10	pF
Power Dissipation Capacitance (Notes 5, 6)	C _{PD}	-	5	38	-	-	-	pF

CD54/74HC174, CD54/74HCT174

Switching Specifications Input $t_r, t_f = 6\text{ns}$ (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS	V _{CC} (V)	25°C		-40°C TO 85°C	-55°C TO 125°C	UNITS
				TYP	MAX	MAX	MAX	
HCT TYPES								
Propagation Delay, Clock to Q	t _{PLH} , t _{PHL}	C _L = 50pF	4.5	-	40	50	60	ns
		C _L = 15pF	5	17	-	-	-	ns
Propagation Delay, $\overline{MR}$ to Q	t _{PLH} , t _{PHL}	C _L = 50pF	4.5	-	44	55	66	ns
		C _L = 15pF	5	18	-	-	-	ns
Output Transition Times	t _{TLH} , t _{THL}	C _L = 50pF	4.5	-	15	19	22	ns
Input Capacitance	C _{IN}	-	-	-	10	10	10	pF
Power Dissipation Capacitance (Notes 5, 6)	C _{PD}	-	5	44	-	-	-	pF

NOTES:

5. C_{PD} is used to determine the dynamic power consumption, per flip-flop.
6. $P_D = V_{CC}^2 f_i + \sum (C_L V_{CC}^2 + f_O)$ where f_i = Input Frequency, f_O = Output Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

Test Circuits and Waveforms

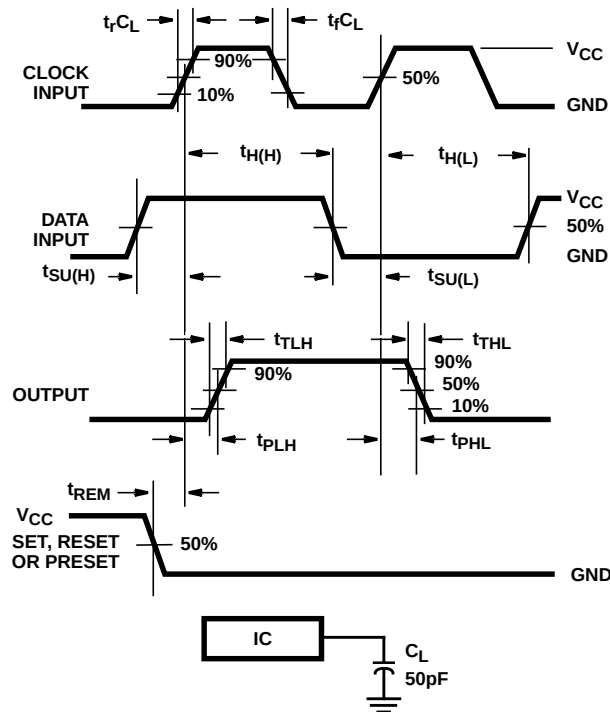


FIGURE 1. HC SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

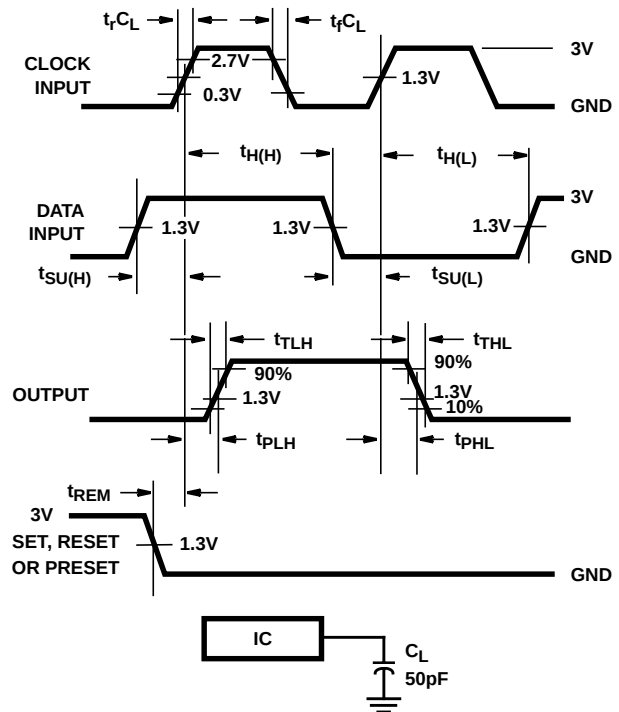


FIGURE 2. HCT SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

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